



PHYSICAL ELECTRONICS GMBH

MS² Workshop: Parallel Imaging MS/MS

Maastricht, 29/30 March 2017 –Physical Electronics GmbH organized together with Physical Electronics USA and Maastricht for Imaging (M4I) at the Maastricht University a Parallel Imaging MS/MS Workshop.

Dr. Gregory Fisher and Prof. Dr. Ron Heeren showed the participants the Worldwide First Installed nanoTOF-II TOF-SIMS with Parallel Imaging MS/MS Instrument at Maastricht University (M4I) which is CHANGING TOF-SIMS FROM I THINK, TO I KNOW!

The participants from industry and university were impressed from this breakthrough technology in TOF-SIMS, surface science research. Unambiguous identification of molecules in biological and materials specimens at high practical lateral resolution is realizable. High mass peaks can be identified easily. Wednesday afternoon we all had the possibility to visit Prof. Dr. Ron Heeren's lab (Director M4I Division Head Imaging Mass Spectrometry) for measuring some samples.



Physical Electronics GmbH thanks again all participants and interested persons and is looking forward to Welcome You soon.



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